

Title (en)

APPARATUS AND METHOD FOR INSPECTING EDGE DEFECT AND DISCOLORATION OF GLASS SUBSTRATE

Title (de)

VORRICHTUNG UND VERFAHREN ZUR RANDDEFEKTEINSPEKTION UND ENTFÄRBUNG VON EINEM GLASSUBSTRAT

Title (fr)

APPAREIL ET PROCEDE POUR INSPECTER UN DEFAUT DE BORD ET LA DECOLORATION D'UN SUBSTRAT DE VERRE

Publication

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Application

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Priority

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Abstract (en)

[origin: WO2006093381A1] Provided are an apparatus and method for inspecting an edge defect and discoloration. The apparatus includes a loading unit for conveying a glass substrate used to manufacture a thin film transistor liquid crystal display; an inspection unit for inspecting edge defects and discoloration of the glass substrate conveyed by the loading unit; and a control unit for controlling the loading unit and the inspection unit. The edge defect and discoloration inspection apparatus is capable of automatically performing edge defect and discoloration inspection of a glass substrate during processes of manufacturing a thin film transistor liquid crystal display. In addition, it is possible to dispose the edge defect and discoloration inspection apparatus between deposition, etching and sputtering processes to confirm whether the glass substrate is good or bad in real time, thereby performing an economic and rapid process.

IPC 8 full level

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